# EE 330 Lecture 35

Telescopic Cascode OpAmp

**Amplifier Biasing** 

**Other Amplifier Structures** 

**Frequency-Dependent Performance of Amplifiers** 

Parasitic Capacitances in MOS Devices

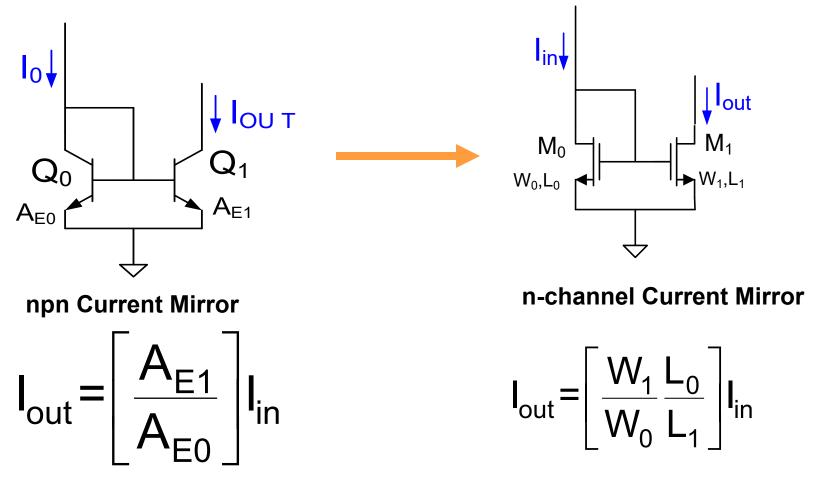
## Fall 2024 Exam Schedule

Exam 1FridayExam 2FridayExam 3FridayFinal ExamMonday

Sept 27 October 25 Nov 22 Dec 16 12:00 - 2:00 PM

#### Review From Previous Lecture

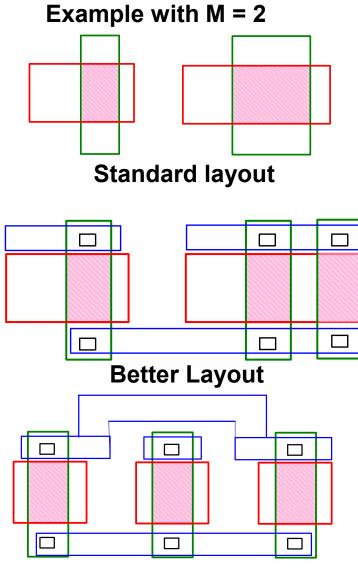
## **Current Sources/Mirrors Summary**



- Current mirror gain can be accurately controlled !
- Layout is important to get accurate gain (for both MOS and BJT)

#### **Review From Previous Lecture**

# Layout of Current Mirrors



**Even Better Layout** 

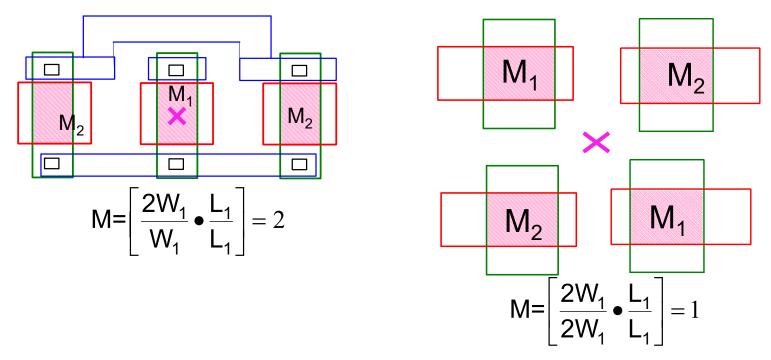
$$\mathsf{M} = \left[\frac{\mathsf{W}_2}{\mathsf{W}_1}\frac{\mathsf{L}_1}{\mathsf{L}_2}\right]$$

$$\mathsf{M} = \left[\frac{2\mathsf{W}_1 + 4\Delta\mathsf{W}}{\mathsf{W}_1 + 2\Delta\mathsf{W}} \bullet \frac{\mathsf{L}_1 + 2\Delta\mathsf{L}}{\mathsf{L}_1 + 2\Delta\mathsf{L}}\right] = 2$$

$$\mathsf{M} = \left[\frac{2\mathsf{W}_1 + 4\Delta\mathsf{W}}{\mathsf{W}_1 + 2\Delta\mathsf{W}} \bullet \frac{\mathsf{L}_1 + 2\Delta\mathsf{L}}{\mathsf{L}_1 + 2\Delta\mathsf{L}}\right] = 2$$

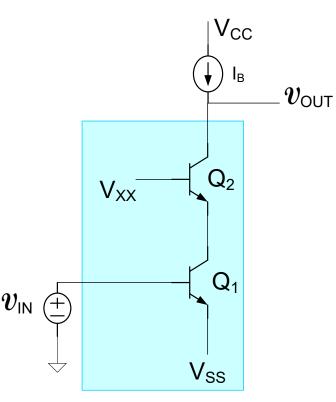
- This is termed a common-centroid layout
- Linear gradient mismatch eliminated with common-centroid layout !

### Review From Previous Lecture Common-Centroid Layouts



- Individual transistors often decomposed into parallel multiple unary devices connected in parallel
- Common-Centroid layout approach widely used to minimize (ideally cancel) gradient effects in matching-critical circuits
- Applications extend well beyond current mirrors
- More than 2 devices can share a common centroid

### Review From Previous Lecture Cascode Configuration Discuss

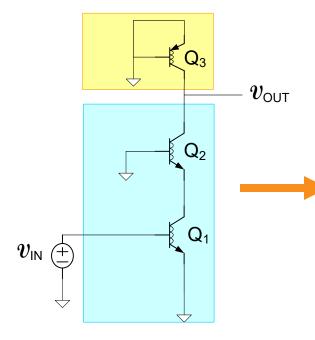


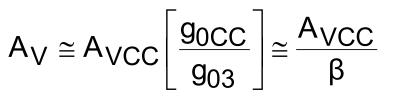
$$A_{VCC} \cong -\left[\frac{g_{m1}}{g_{02}}\beta\right] \cong -\left[\frac{g_{m1}}{g_{01}}\right]\beta$$
$$g_{0CC} \cong \frac{g_{02}}{\beta}$$
$$A_{VCC} \cong -\left[\frac{g_{m1}}{g_{01}}\right]\beta = \left[\frac{2V_{AF}}{V_{t}}\right]\beta = \left[-8000\right]100$$
$$A_{VCC} \cong -800,000$$

This gain is very large and only requires two transistors!

What happens to the gain if a transistor-level current source is used for  $I_B$ ?

### Review From Previous Lecture Cascode Configuration





But recall

$$A_{VCC} \cong - \left\lfloor \frac{g_{m1}}{g_{01}} \right\rfloor \beta$$

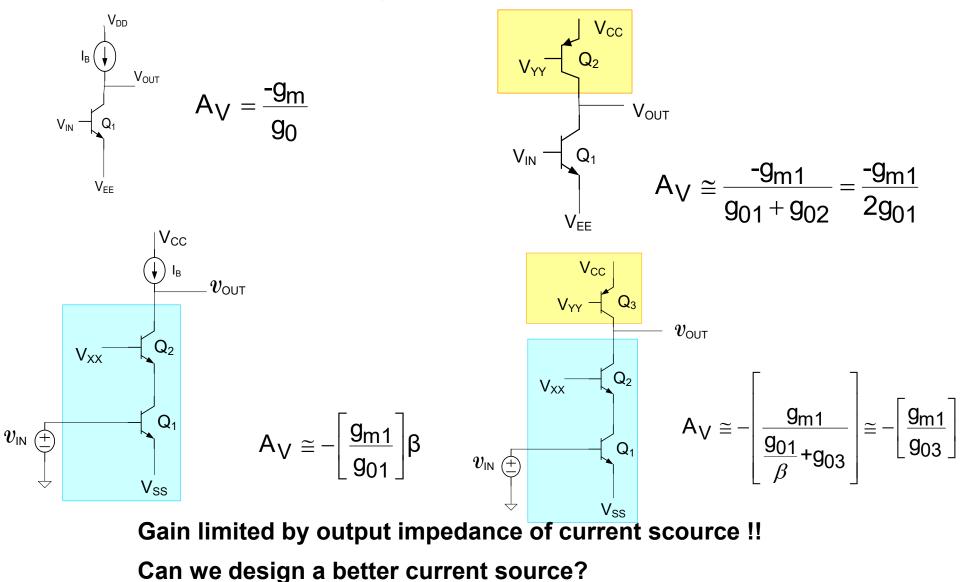
Thus  

$$A_{V} \cong -\left[\frac{g_{m1}}{g_{01}}\right]$$

$$A_{V} \cong -\left[\frac{I_{CQ}}{V_{t}}\right] = -\left[\frac{V_{AF}}{V_{t}}\right] \cong -8000$$

- This is still a factor of 2 better than that of the CE amplifier with transistor current source  $\begin{pmatrix} A_{VCE} \cong \left\lceil \frac{g_{m1}}{2g_{01}} \right\rceil \end{pmatrix}$
- It only requires one additional transistor
- But its not nearly as good as the gain the cascode circuit seemed to provide

#### Review From Previous Lecture Cascode Configuration Comparisons

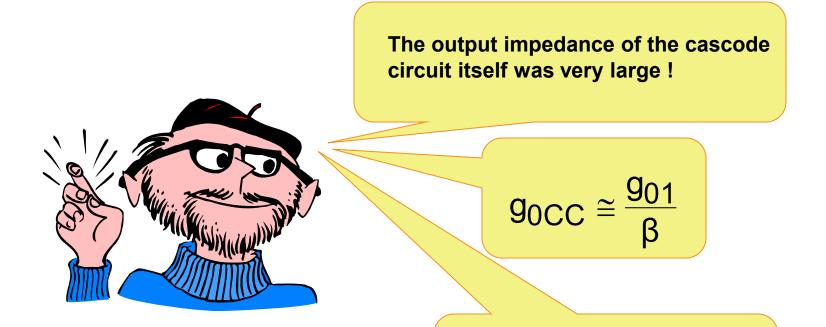


In particular, one with a higher output impedance?

**Review From Previous Lecture** 

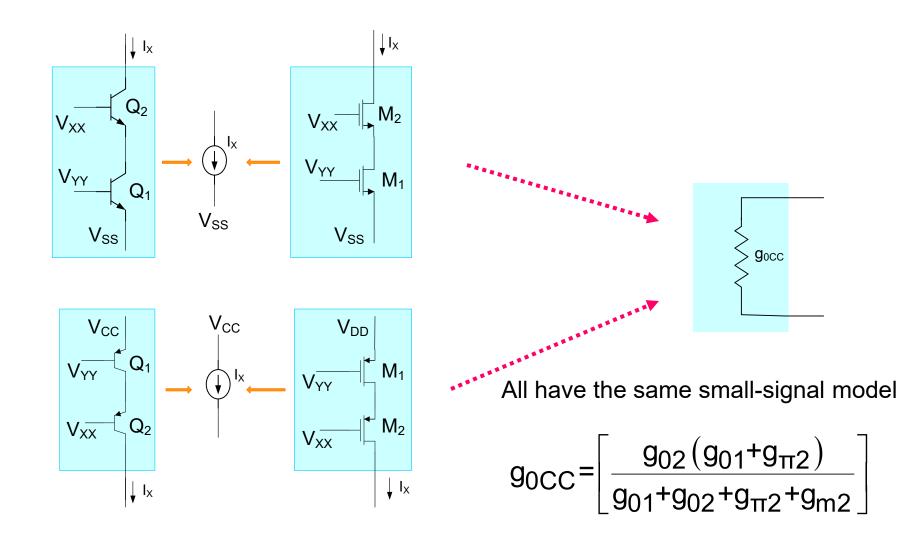
## Better current sources

### Need a higher output impedance than g<sub>o</sub>

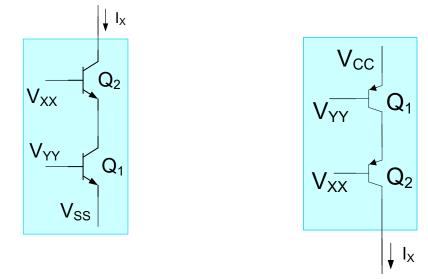


Can a current source be built with the cascode circuit ?

## Cascode current sources

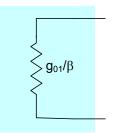


## Cascode current sources



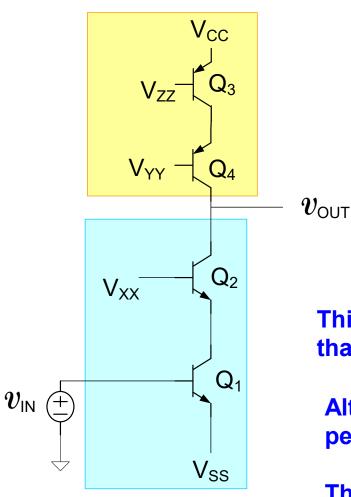
For the BJT cascode current sources

$$g_{0CC} = \left[\frac{g_{02}(g_{01} + g_{\pi 2})}{g_{01} + g_{02} + g_{\pi 2} + g_{m 2}}\right] \cong \left[\frac{g_{02}g_{\pi 2}}{g_{m 2}}\right] = \frac{g_{01}}{\beta}$$



### Review From Previous Lecture Cascode Configuration





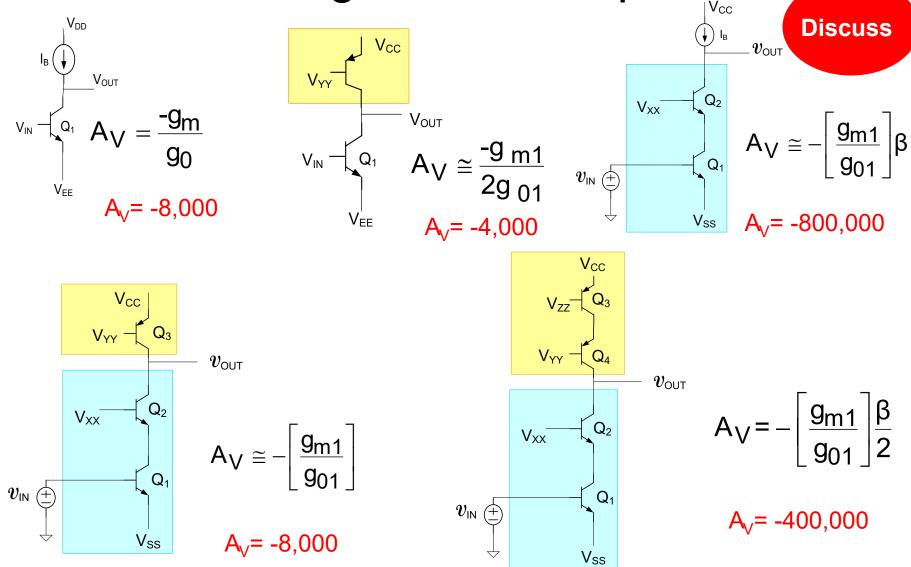
$$A_{V} = -\left[\frac{g_{m1}}{g_{01}}\right]\frac{\beta}{2}$$
$$A_{V} = -\left[8000\right]\frac{100}{2} \approx -400,000$$

This gain is very large and is a factor of 2 below that obtained with an ideal current source biasing

Although the factor of 2 is not desired, the performance of this circuit is still very good

This factor of 2 gain reduction is that same as was observed for the CE amplifier when a transistorlevel current source was used

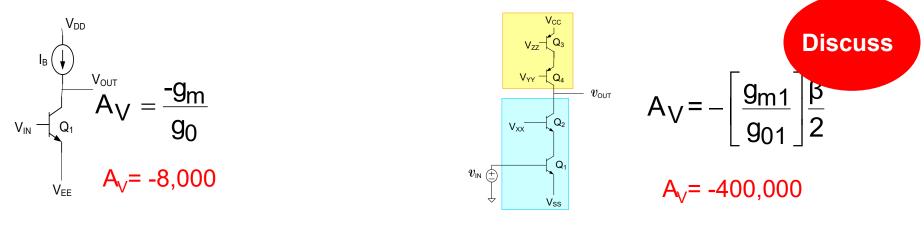
### Review From Previous Lecture Cascode Configuration Comparisons

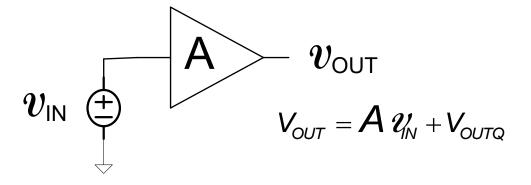


#### Can we use more cascoding to further increase the gain?

**Review From Previous Lecture** 

## High Gain Amplifiers Seldom Used Open Loop

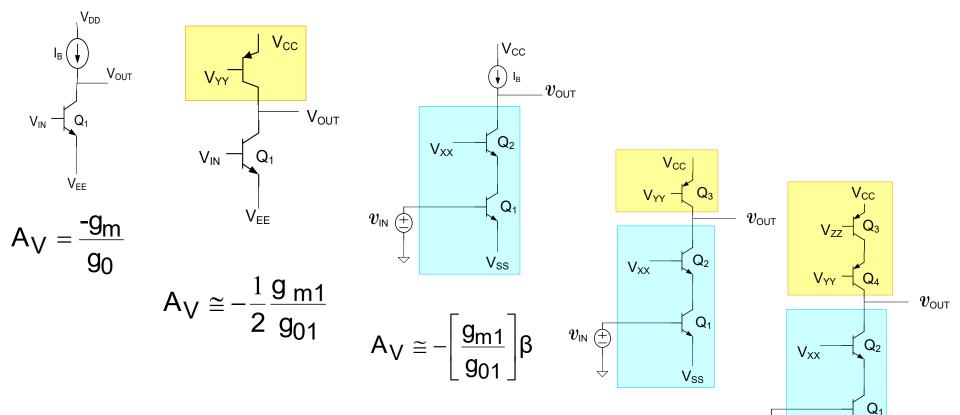




If  $A_V$ =-400,000 and  $V_{IN}$  increases by 1mV, what would happen at the output?

 $V_{OUT}$  would decrease by 400,000 x 1mV=-400V

### Review From Previous Lecture High Gain Amplifier Comparisons (BJT)



 $A_V \cong - \left| \frac{g_{m1}}{g_{01}} \right|$ 

 $v_{ ext{in}}$   $\pm$ 

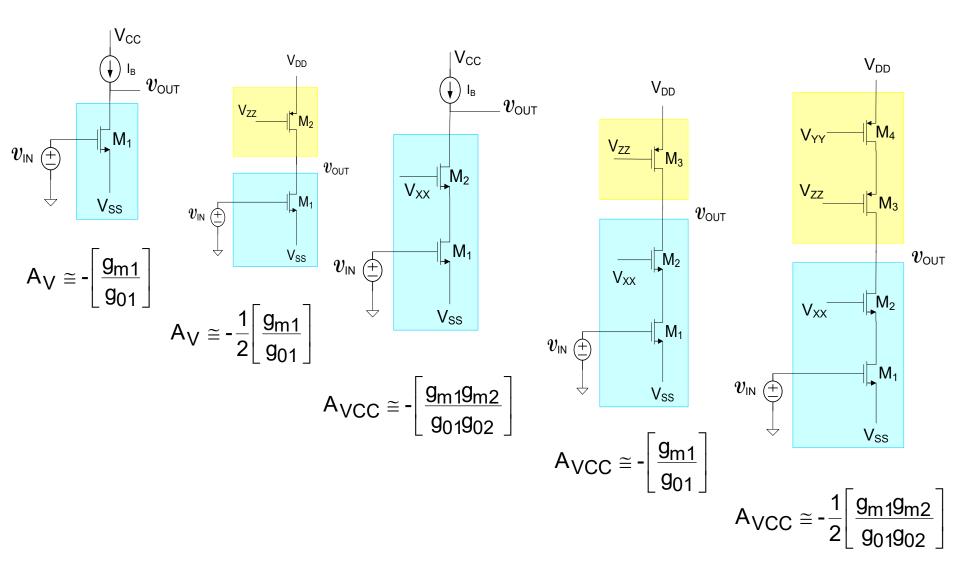
 $A_V = -$ 

Vss

 $\frac{g_{m1}}{g_{m1}}$ 

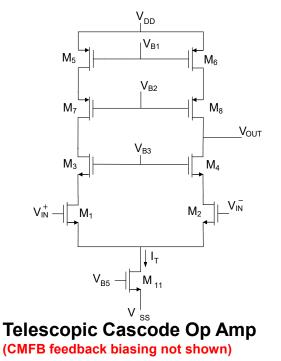
- Single-ended high-gain amplifiers inherently difficult to bias (because of the high gain)
- Biasing becomes practical when used in differential applications
- These structures are widely used but usually with differential inputs

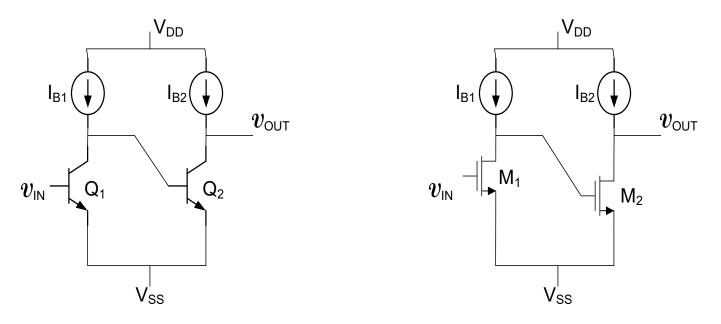
#### Review From Previous Lecture High Gain Amplifier Comparisons (n-ch MOS)



### **The Cascode Amplifier**

- Operational amplifiers often built with basic cascode configuration
- CMFB used to address the biasing problem
- Usually configured as a differential structure when building op amps
- Have high output impedance (but can be bufferred)
- Terms "telescopic cascode", "folded-cascode", and "regulated cascode" often refer to op amps based upon the cascode configuration

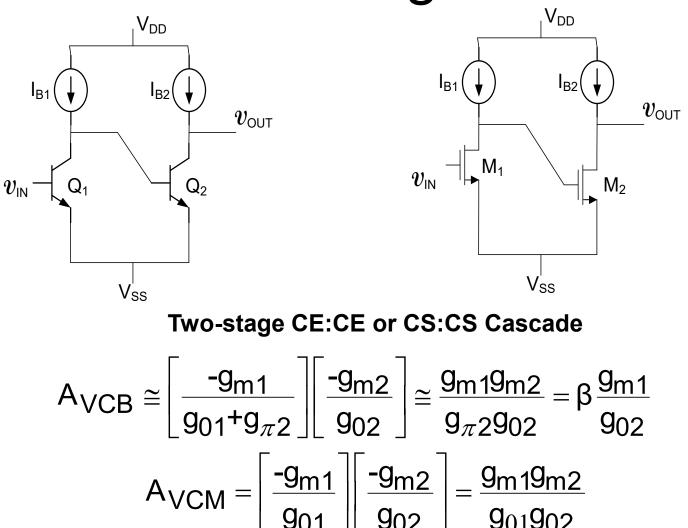




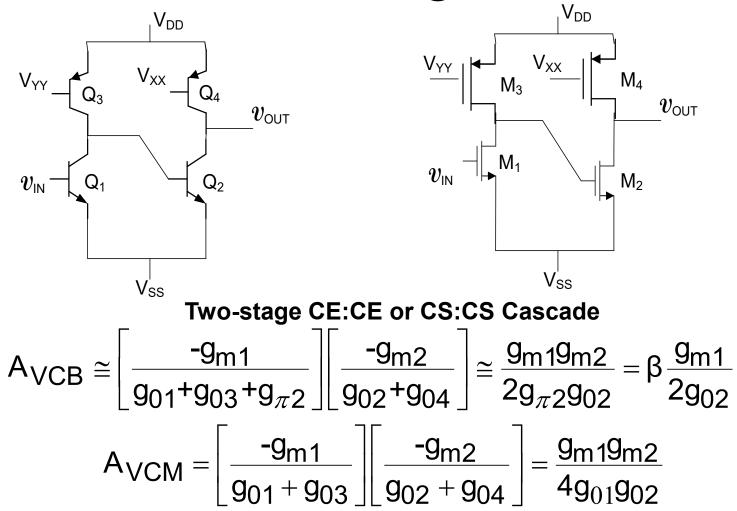
Two-stage CE:CE or CS:CS Cascade

 $A_{VCB} = ?$ 

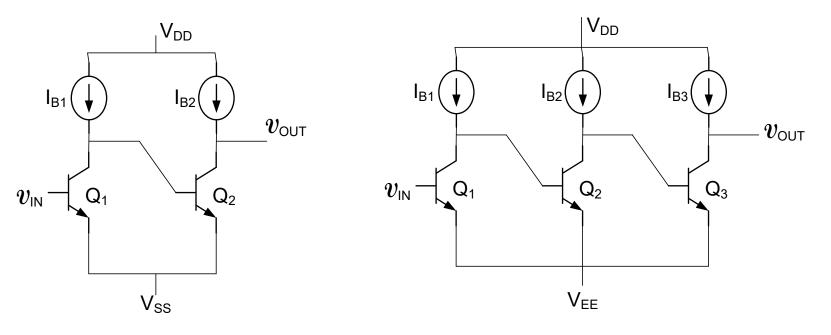
 $A_{VCM} = ?$ 



- Significant increase in gain
- Gain is noninverting
- Comparable to that obtained with the cascode but noninverting



Note factor or 2 and 4 reduction in gain due to actual current source bias

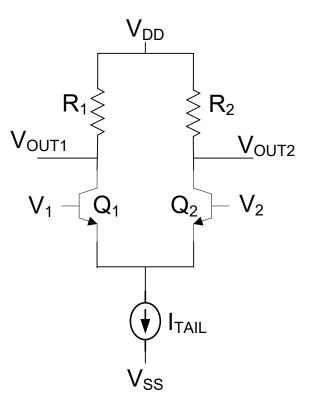


#### **Two-stage CE Cascade**

**Three-stage CE Cascade** 

- Large gains can be obtained by cascading
- Gains are multiplicative (when loading is included)
- Large gains used to build "Op Amps" and feedback used to control gain value
- Some attention is needed for biasing but it is manageable
- Minor variant of the two-stage cascade often used to build Op Amps
- Compensation of two-stage cascade needed if feedback is applied to maintain stability
- For many years three or more stages were seldom cascaded because of challenges in compensation to maintain stability though recently some industrial adoptions

# **Differential Amplifiers**



Basic operational amplifier circuit

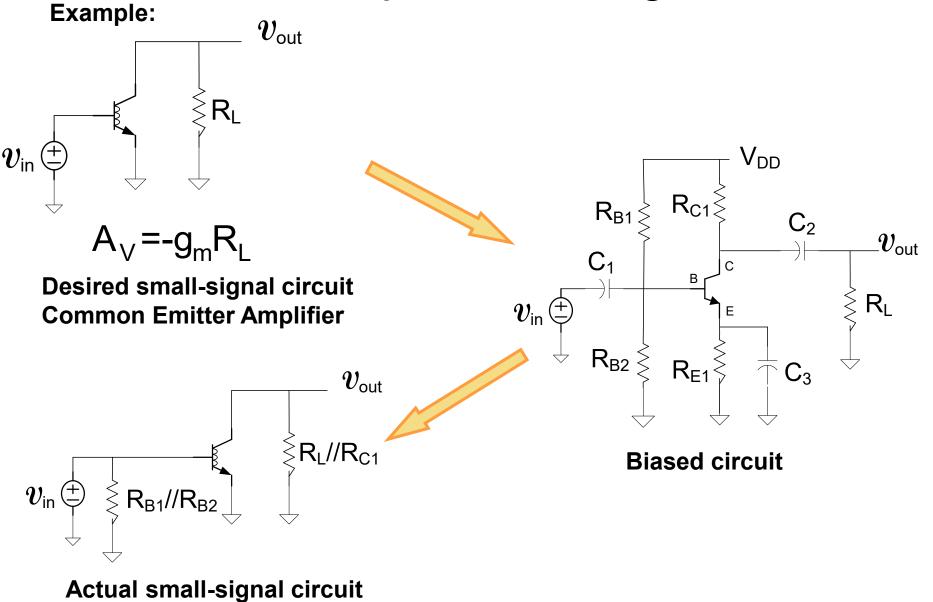
Amplifier biasing is that part of the design of a circuit that establishes the desired operating point (or Q-point)

Goal is to invariably minimize the impact the biasing circuit has on the small-signal performance of a circuit

Usually at most 2 dc power supplies are available and these are often fixed in value by system requirements – this restriction is cost driven

Discrete amplifiers invariable involve adding biasing resistors and use capacitor coupling and bypassing

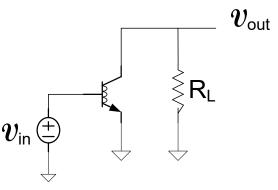
Integrated amplifiers often use current sources which can be used in very large numbers and are very inexpensive



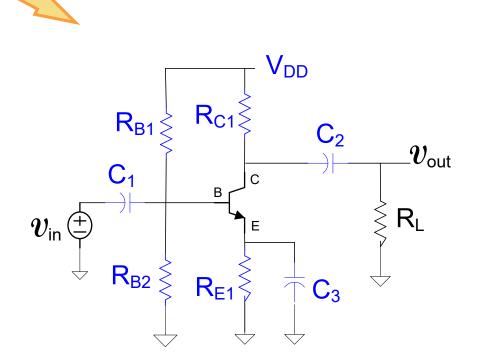
$$A_{V} = -g_{m}(R_{L} //R_{C1})$$

Biasing components shown in blue

#### Example:

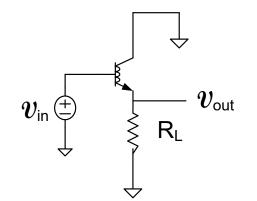


Desired small-signal circuit Common Emitter Amplifier

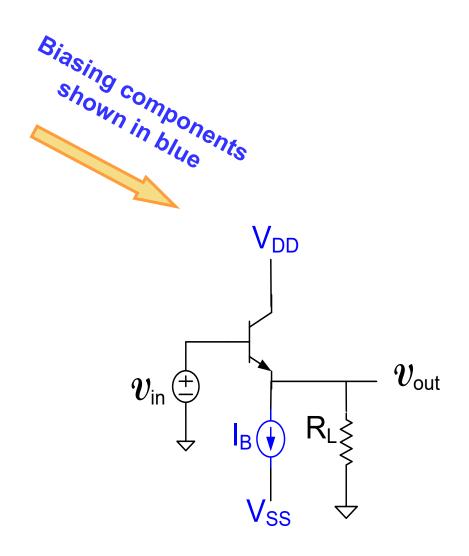


**Biased small-signal circuit** 

#### Example:

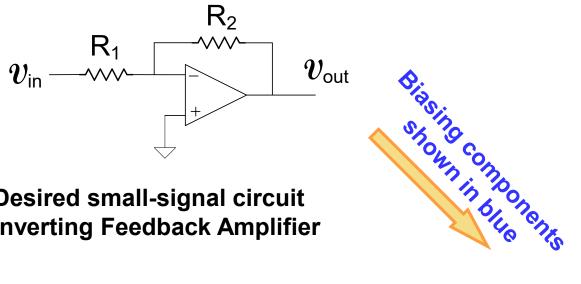


Desired small-signal circuit Common Collector Amplifier

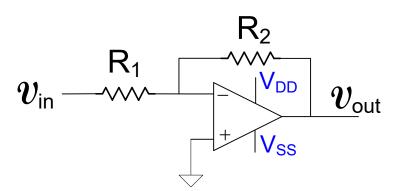


**Biased circuit** 

#### **Example:**

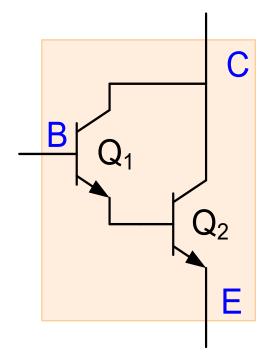


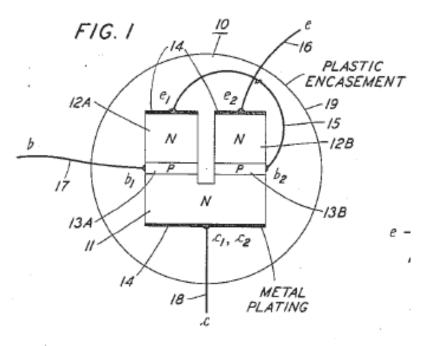
**Desired small-signal circuit Inverting Feedback Amplifier** 



**Biased circuit** 

## **Other Basic Configurations**





**Darlington Configuration** 

S. DARLINGTON

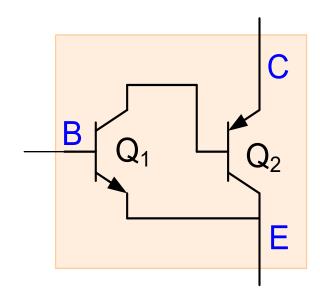
2,663,806

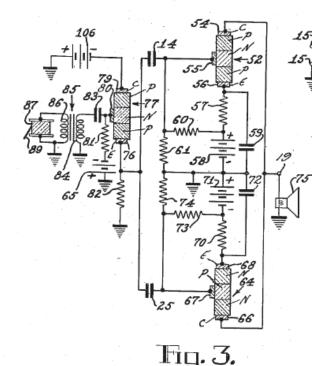
SEMICONDUCTOR SIGNAL TRANSLATING DEVICE

Filed May 9, 1952

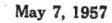
- Current gain is approximately β<sup>2</sup>
- Two diode drop between B<sub>eff</sub> and E<sub>eff</sub>

## Other Basic Configurations





Sziklai Pair

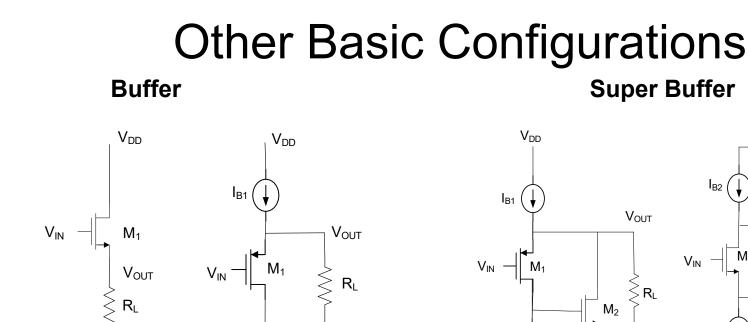


2,791,644

G. C. SZIKLAI PUSH-PULL AMPLIFIER WITH COMPLEMENTARY TYPE TRANSISTORS

Filed Nov. 7, 1952

- Gain similar to that of Darlington Pair
- Current gain is approximately  $\beta_n \beta_p$
- Current gain will not be as large when  $\beta_p < \beta_n$
- Only one diode drop between B<sub>eff</sub> and E<sub>eff</sub>



Ideally  $V_{OUT} = V_{IN}$ 

ӡ

Assume load terminated on gnd Current through  $M_1$  changes with  $V_{IN}$  Voltage shift varies with  $V_{IN}$  in buffer

ケ

Assume load terminated on gnd

Ideally  $V_{OUT} = V_{IN}$ 

I<sub>B2</sub>

Current through shift transistor is constant for Super Buffer as  $V_{\rm IN}$  changes so voltage shift does not change with  $V_{\rm IN}$ 

I<sub>B1</sub>

(optional)

 $V_{DD}$ 

 $M_2$ 

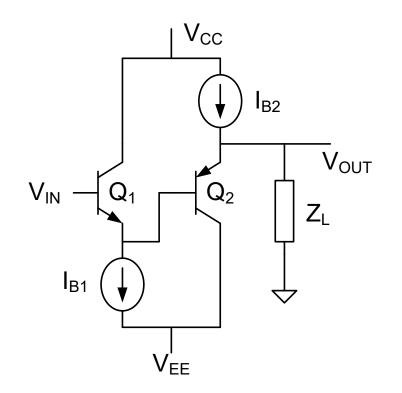
VOUT

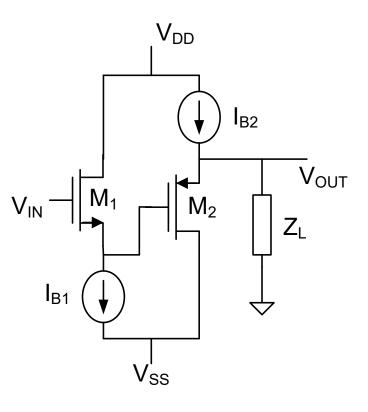
 $R_L$ 

Same nominal voltage shift as buffer

## **Other Basic Configurations**

#### Low offset buffers

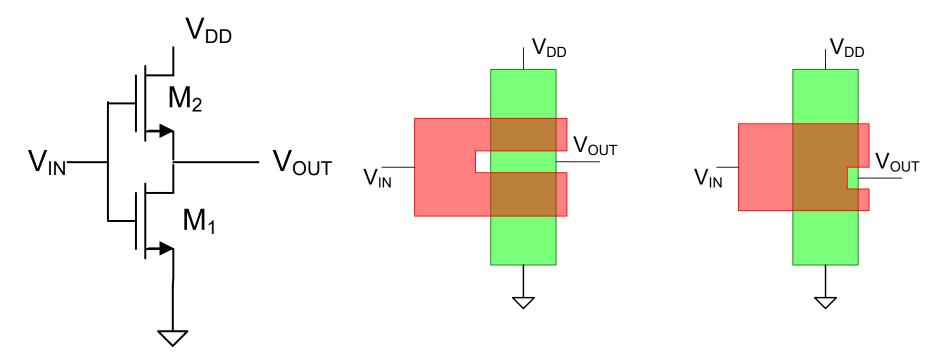




- Actually a CC-CC or a CD-CD cascade
- Significant drop in offset between input and output
- Biasing with DC current sources
- Can Add Super Buffer to Output

## **Other Basic Configurations**

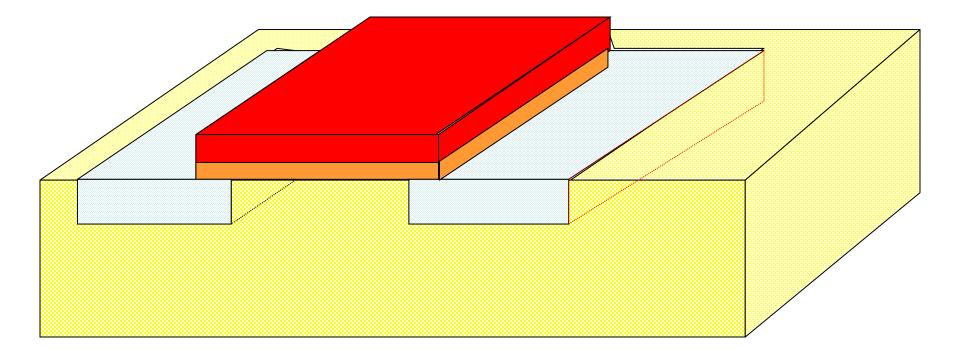
**Voltage Attenuator** 



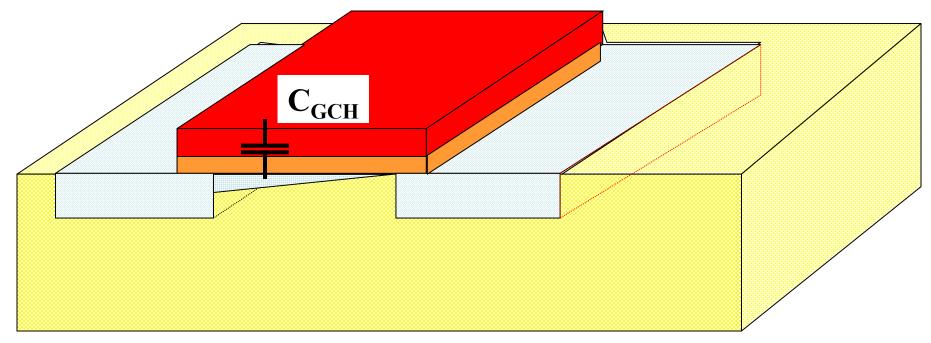
- Attenuation factor is quite accurate (Determined by geometry)
- Infinite input impedance
- M<sub>1</sub> in triode, M<sub>2</sub> in saturation
- Actually can be a channel-tapped structure

### **Frequency-Dependent Performance of Amplifiers**

# Parasitic Capacitors in MOSFET

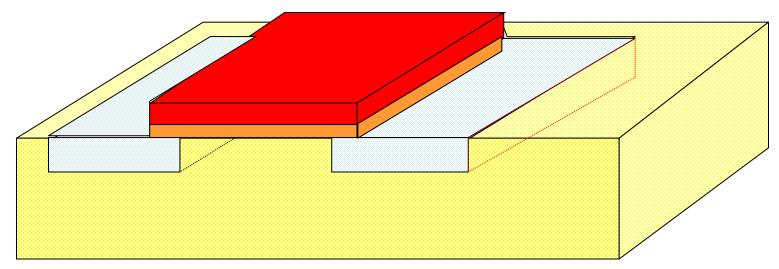


# Parasitic Capacitors in MOSFET

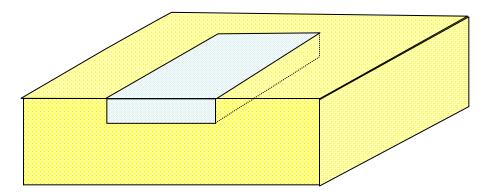


- This capacitance was modeled previously and exists when the transistor is operating in triode or saturation
- But there are others that also affect high-frequency or high-speed operation

# Parasitic Capacitors in MOSFET

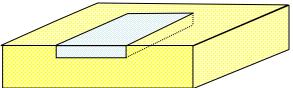


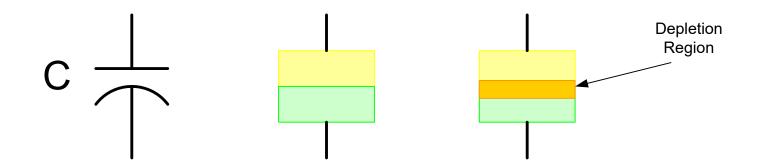
Recall that pn junctions have a depletion region!

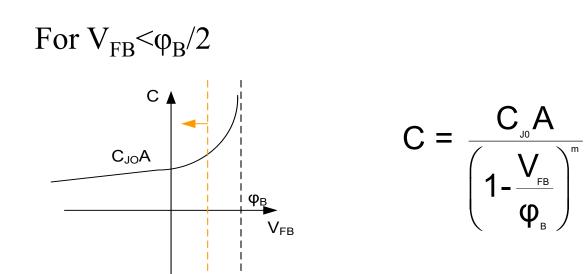


# Parasitic Capacitors in MOSFET

pn junction capacitance

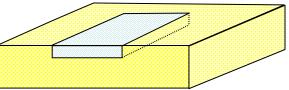




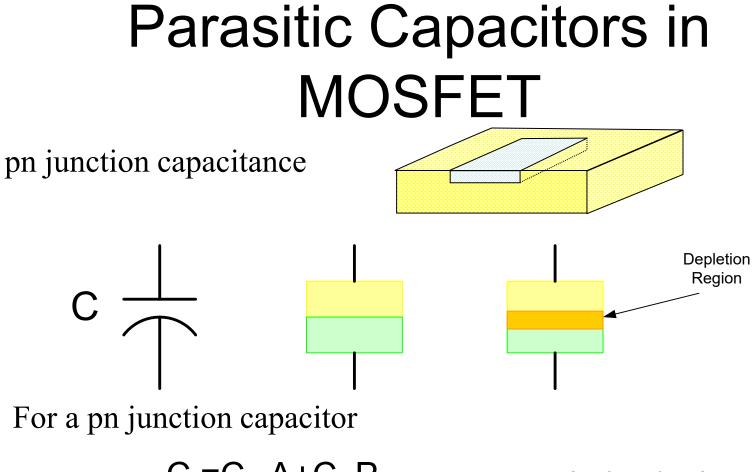


# Parasitic Capacitors in MOSFET

pn junction capacitance



The bottom and the sidewall:



 $C_{BOT} = \frac{C_{BOT}}{\left(1 - \frac{V_{FB}}{\phi_{B}}\right)^{m}} \qquad C_{SW} = \frac{C_{SW0}}{\left(1 - \frac{V_{FB}}{\phi_{B}}\right)^{m}} \qquad V$ 

 $C_{BOT}$  and  $C_{SW}$  are capacitance densities

A : Junction Area P: Junction Perimeter V<sub>FB</sub>: forward bias on junction

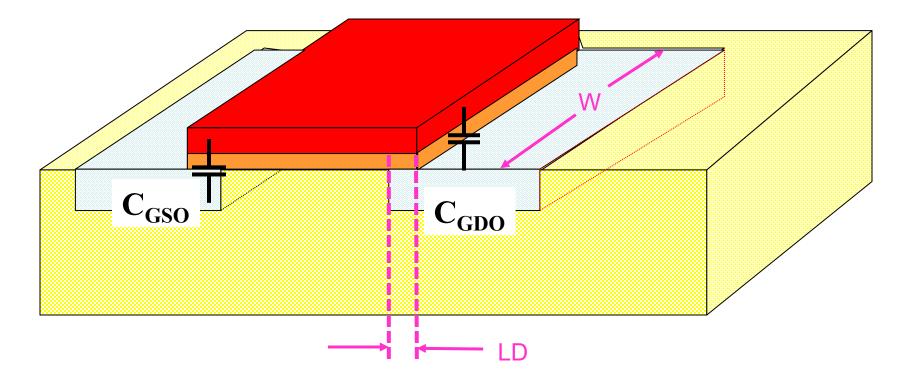
Model Parameters:

 $\{C_{BOT0},C_{SW0},\phi_B,m\}$ 

## Types of Capacitors in MOSFETs

- 1. Fixed Capacitors
- a. Fixed Geometry
  - b. Junction
  - 2. Operating Region Dependent

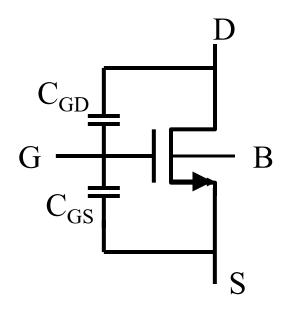
# Parasitic Capacitors in MOSFET Fixed Capacitors – Fixed Geometry



Overlap Capacitors:  $C_{GDO}$ ,  $C_{GSO}$ L<sub>D</sub>: lateral diffusion

Cap Density: C<sub>OX</sub>

# Parasitic Capacitance Summary (partial)



	Cutoff	Ohmic	Saturation
C <sub>GSO</sub>	CoxWL <sub>D</sub>	CoxWL <sub>D</sub>	CoxWL <sub>D</sub>
$C_{GDO}$	CoxWL <sub>D</sub>	CoxWL <sub>D</sub>	CoxWL <sub>D</sub>

#### $L_{\text{D}}$ is a model parameter

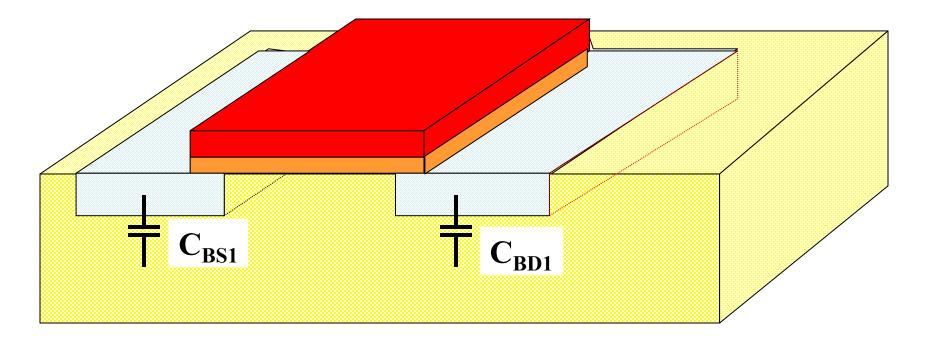
### **Overlap Capacitance Model Parameters**

CAPACITANCE PARAMETERS	N+	P+ POLY	M1	М2	MЗ	Μ4	М5	М6	RW	D N W M5P	NW	UNITS
Area (substrate)	942	1163 106	34	14	9	6	5	3	_	123	125	aF/um^2
Area (N+active)		8484	55	20	13	11	9	8				aF/um^2
Area (P+active)		8232										aF/um^2
Area (poly)			66	17	10	7	5	4				aF/um^2
Area (metal1)				37	14	9	6	5				aF/um^2
Area (metal2)					35	14	9	6				aF/um^2
Area (metal3)						37	14	9				aF/um^2
Area (metal4)							36	14				aF/um^2
Area (metal5)								34		9	84	aF/um^2
Area (r well)	920	)										aF/um^2
Area (d well)									582			aF/um^2
Area (no well)	137	7										aF/um^2
Fringe (substrate)	212	2 235	41	35	29	21	14					aF/um
Fringe (poly)			70	39	29	23	20	17				aF/um
Fringe (metal1)				52	34		22	19				aF/um
Fringe (metal2)					48	35	27	22				aF/um
Fringe (metal3)						53	34	27				aF/um
Fringe (metal4)							58	35				aF/um
Fringe (metal5)								55				aF/um
Overlap (N+active)		89	5									aF/um
Overlap (P+active)		73	7)									aF/um

## Types of Capacitors in MOSFETs

- 1. Fixed Capacitors
  - a. Fixed Geometry
- b. Junction
  - 2. Operating Region Dependent

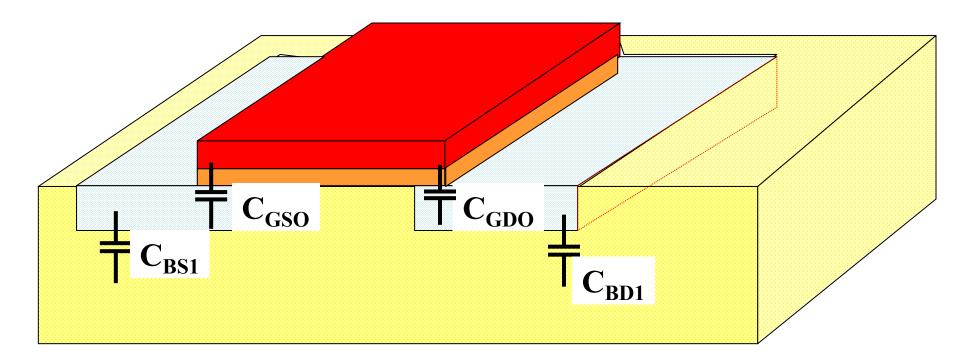
## Parasitic Capacitors in MOSFET Fixed Capacitors-Junction



Junction Capacitors: C<sub>BS1</sub>, C<sub>BD1</sub>

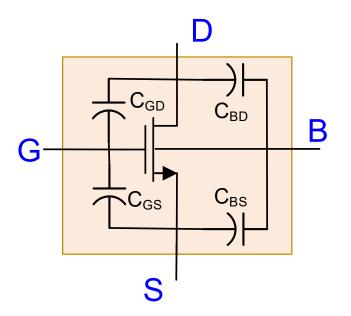
## Parasitic Capacitors in MOSFET

- Fixed Capacitors



Overlap Capacitors:  $C_{GDO}$ ,  $C_{GSO}$ Junction Capacitors:  $C_{BS1}$ ,  $C_{BD1}$ 

## Fixed Parasitic Capacitance Summary



 $C_{BOT}$  and  $C_{SW}$  are model parameters

	Cutoff	Ohmic	Saturation
C <sub>GSO</sub>	CoxWL <sub>D</sub>	CoxWL <sub>D</sub>	CoxWL <sub>D</sub>
$C_{GDO}$	CoxWL <sub>D</sub>	CoxWL <sub>D</sub>	CoxWL <sub>D</sub>
C <sub>BG</sub>			
C <sub>BS</sub>	$C_{BS1} = C_{BOT}A_S + C_{SW}P_S$	$C_{BS1} = C_{BOT}A_S + C_{SW}P_S$	$C_{BS1} = C_{BOT}A_S + C_{SW}P_S$
C <sub>BD</sub>	$C_{BD1} = C_{BOT}A_{D} + C_{SW}P_{D}$	$C_{BD1} = C_{BOT}A_{D} + C_{SW}P_{D}$	$C_{BD1} = C_{BOT}A_D + C_{SW}P_D$

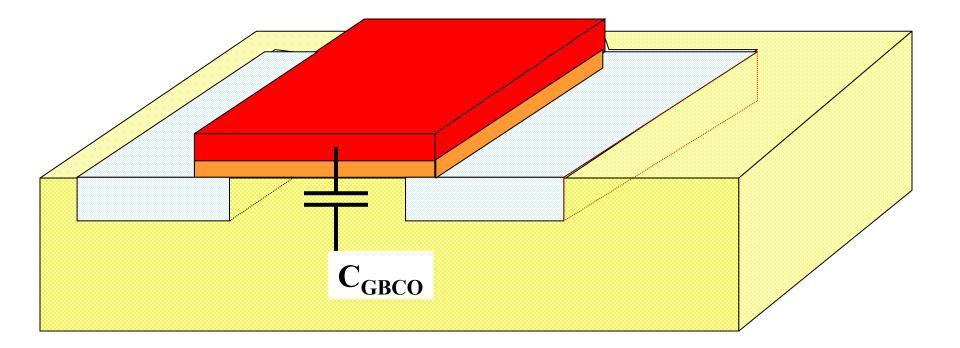
## $C_{BOT}$ and $C_{SW}$ model parameters

CAPACITANCE PARAMETERS N+ P+ POLY	M1	M2	МЗ	M4	М5	Μ6	R_W	D_N_W M5P	N_W	UNITS
Area (substrate) 942(1163)106	34	14	9	6	5	3		123	125	aF/um^2
Area (N+active) 8484	55	20	13	11	9	8				aF/um^2
Area (P+active) 8232										aF/um^2
Area (poly)	66	17	10	7	5	4				aF/um^2
Area (metal1)		37	14	9	6	5				aF/um^2
Area (metal2)			35	14	9	6				aF/um^2
Area (metal3)				37	14	9				aF/um^2
Area (metal4)					36	14				aF/um^2
Area (metal5)						34		9	84	aF/um^2
Area (r well) 920										aF/um^2
Area (d well)							582			aF/um^2
Area (no well) 137										aF/um^2
Fringe (substrate) (212)(235)	41	35	29	21	14					aF/um
Fringe (poly)	70	39	29	23	20	17				aF/um
Fringe (metal1)		52	34		22	19				aF/um
Fringe (metal2)			48	35	27	22				aF/um
Fringe (metal3)				53	34	27				aF/um
Fringe (metal4)					58	35				aF/um
Fringe (metal5)						55				aF/um
Overlap (N+active) 895	5									aF/um
Overlap (P+active) 73	7									aF/um

## Types of Capacitors in MOSFETs

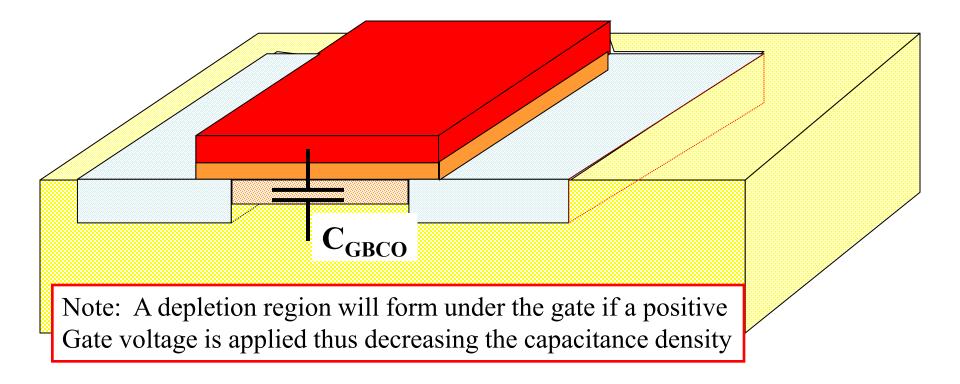
- 1. Fixed Capacitors
  - a. Fixed Geometry
  - b. Junction
- **2**. Operating Region Dependent

## Parasitic Capacitors in MOSFET Operation Region Dependent -- Cutoff



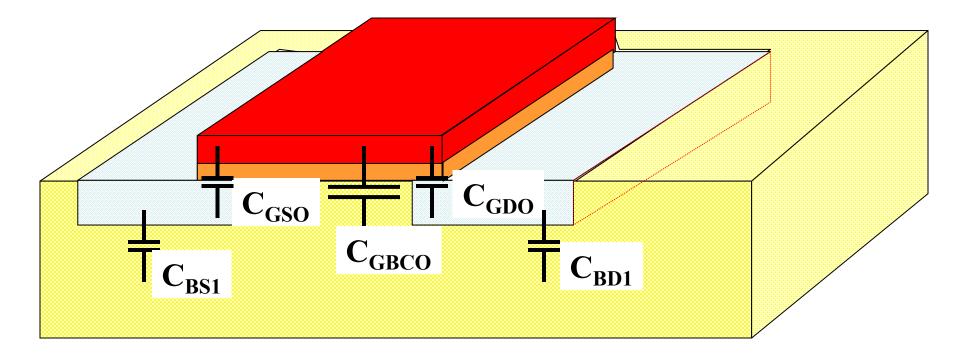
### **Cutoff Capacitor: C**<sub>GBCO</sub>

## Parasitic Capacitors in MOSFET Operation Region Dependent -- Cutoff



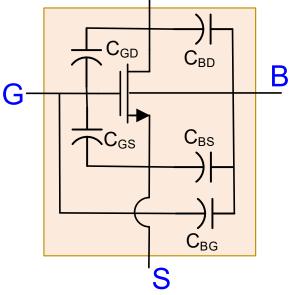
### **Cutoff Capacitor: C**<sub>GBCO</sub>

### Parasitic Capacitors in MOSFET Operation Region Dependent and Fixed -- Cutoff



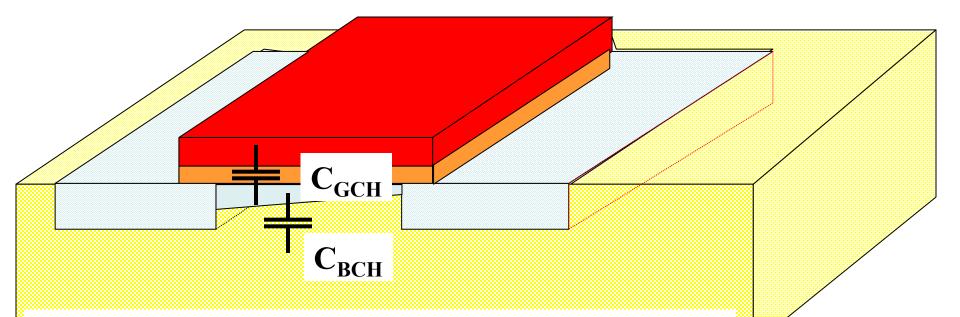
Overlap Capacitors:  $C_{GDO}$ ,  $C_{GSO}$ Junction Capacitors:  $C_{BS1}$ ,  $C_{BD1}$ **Cutoff Capacitor:**  $C_{GBCO}$ 

# Parasitic Capacitance Summary



	Cutoff	Ohmic	Saturation
C <sub>GSO</sub>	CoxWL <sub>D</sub>		
	CoxWL <sub>D</sub>		
C <sub>BG</sub>	CoxWL (or less)		
C <sub>BS</sub>	C <sub>BOT</sub> A <sub>S</sub> +C <sub>SW</sub> P <sub>S</sub>		
C <sub>BD</sub>	$C_{BOT}A_{D}+C_{SW}P_{D}$		

## Parasitic Capacitors in MOSFET Operation Region Dependent -- Ohmic

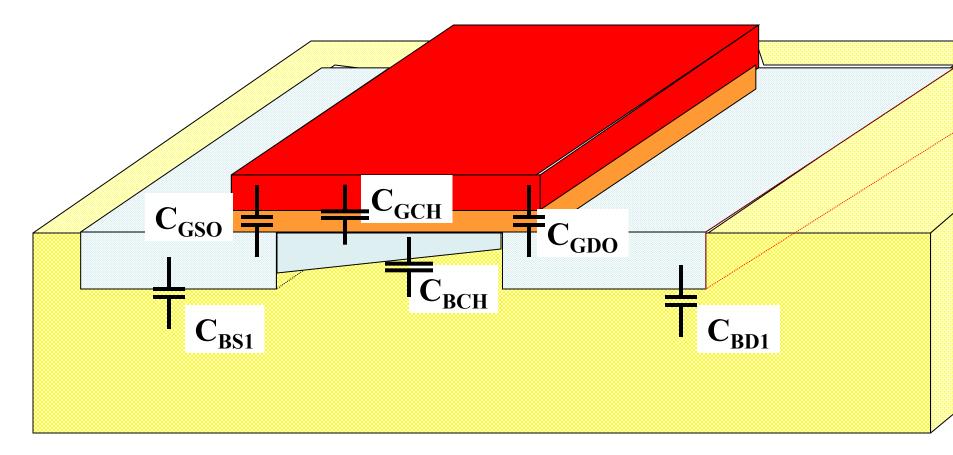


Note: The Channel is not a node in the lumped device model so can not directly include this distributed capacitance in existing models

Note: The distributed channel capacitance is usually lumped and split evenly between the source and drain nodes

### **Ohmic Capacitor:** $C_{GCH}$ , $C_{BCH}$

### Parasitic Capacitors in MOSFET Operation Region Dependent and Fixed -- Ohmic

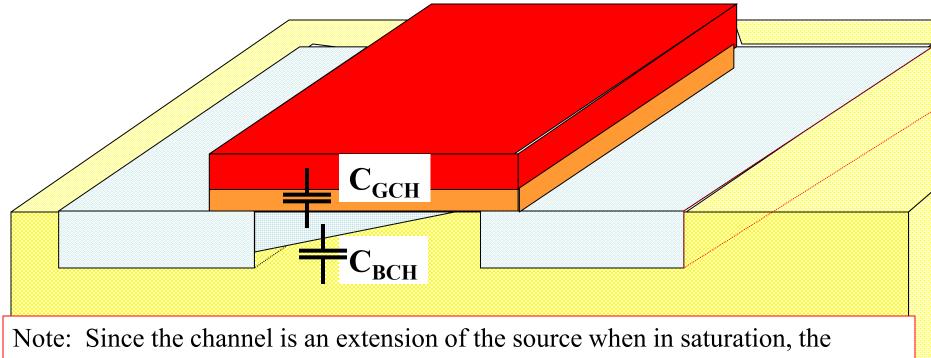


Overlap Capacitors:  $C_{GDO}$ ,  $C_{GSO}$ Junction Capacitors:  $C_{BS1}$ ,  $C_{BD1}$ **Ohmic Capacitor:**  $C_{GCH}$ ,  $C_{BCH}$ 

#### Parasitic Capacitance Summary $\mathsf{C}_{\mathsf{GD}}$ $C_{\text{BD}}$ B G $C_{\text{BS}}$ Lumped $C_{\text{GC}}$ and $C_{\text{BC}}$ to analytically avoid dealing with distributed capacitance $C_{BG}$ S

	Cutoff	Ohmic	Saturation
C <sub>GS</sub>	CoxWL <sub>D</sub>	0.5CoxWL	
	CoxWL <sub>D</sub>	0.5CoxWL	
C <sub>BG</sub>	CoxWL (or less)	0	
C <sub>BS</sub>	$C_{BOT}A_S + C_{SW}P_S$	C <sub>BOT</sub> A <sub>S</sub> +C <sub>SW</sub> P <sub>S</sub> +0.5WLC <sub>BOTCH</sub>	
C <sub>BD</sub>	$C_{BOT}A_D + C_{SW}P_D$	C <sub>BOT</sub> A <sub>D</sub> +C <sub>SW</sub> P <sub>D</sub> +0.5WLC <sub>BOTCH</sub>	

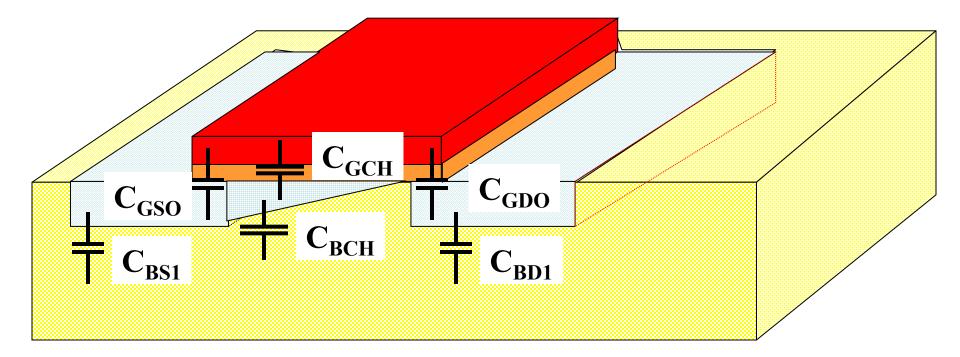
### Parasitic Capacitors in MOSFET Operation Region Dependent -- Saturation



distributed capacitors to the channel are generally lumped to the source node

### Saturation Capacitors: C<sub>GCH</sub>, C<sub>BCH</sub>

### Parasitic Capacitors in MOSFET Operation Region Dependent and Fixed --Saturation



### Overlap Capacitors: $C_{GDO}$ , $C_{GSO}$ Junction Capacitors: $C_{BS1}$ , $C_{BD1}$ **Saturation Capacitors:** $C_{GCH}$ , $C_{BCH}$

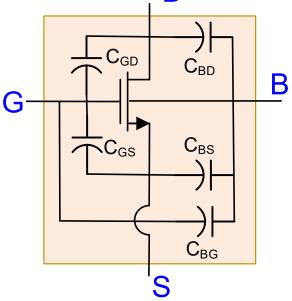
- $2/3 C_{OX}WL$  is often attributed to  $C_{GCH}$  to account for LD and saturation
- This approximation is reasonable for minimum-length devices but not so good for longer devices

#### **Parasitic Capacitance Summary** $C_{GD}$ $C_{BD}$ B G **C**GS $C_{\text{BS}}$ Lumped $C_{GC}$ and $C_{BC}$ to analytically avoid dealing with distributed capacitance $C_{BG}$

	Cutoff	Ohmic	Saturation
C <sub>GS</sub>	CoxWL <sub>D</sub>	0.5C <sub>OX</sub> WL	CoxWL <sub>D</sub> +(2/3)C <sub>OX</sub> WL
	CoxWL <sub>D</sub>	0.5C <sub>OX</sub> WL	CoxWL <sub>D</sub>
C <sub>BG</sub>	CoxWL (or less)	0	0
C <sub>BS</sub>	$C_{BOT}A_{S}+C_{SW}P_{S}$	$C_{BOT}A_{S}+C_{SW}P_{S}+0.5WLC_{BOTCH}$	C <sub>BOT</sub> A <sub>S</sub> +C <sub>SW</sub> P <sub>S</sub> +(2/3)WLC <sub>BOTCH</sub>
C <sub>BD</sub>	$C_{BOT}A_{D}+C_{SW}P_{D}$	$C_{BOT}A_{D}+C_{SW}P_{D}+0.5WLC_{BOTCH}$	$C_{BOT}A_D + C_{SW}P_D$

S

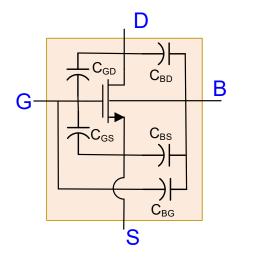
# Parasitic Capacitance Summary

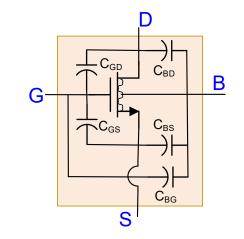


	Cutoff	Ohmic	Saturation
C <sub>GS</sub>	CoxWL <sub>D</sub>	0.5C <sub>OX</sub> WL	CoxWL <sub>D</sub> +(2/3)C <sub>OX</sub> WL
	CoxWL <sub>D</sub>	0.5C <sub>OX</sub> WL	CoxWL <sub>D</sub>
C <sub>BG</sub>	CoxWL (or less)	0	0
C <sub>BS</sub>	$C_{BOT}A_S + C_{SW}P_S$	C <sub>BOT</sub> A <sub>S</sub> +C <sub>SW</sub> P <sub>S</sub> +0.5WLC <sub>BOTCH</sub>	C <sub>BOT</sub> A <sub>S</sub> +C <sub>SW</sub> P <sub>S</sub> +(2/3)WLC <sub>BOTCH</sub>
C <sub>BD</sub>	$C_{BOT}A_D + C_{SW}P_D$	C <sub>BOT</sub> A <sub>D</sub> +C <sub>SW</sub> P <sub>D</sub> +0.5WLC <sub>BOTCH</sub>	$C_{BOT}A_{D}+C_{SW}P_{D}$

#### Observe there is no $C_{DS}$ in this model because does not physically exist

# Parasitic Capacitance Summary

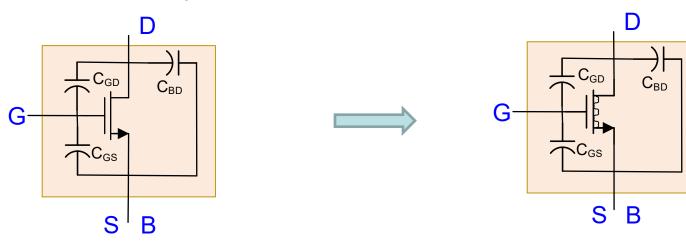




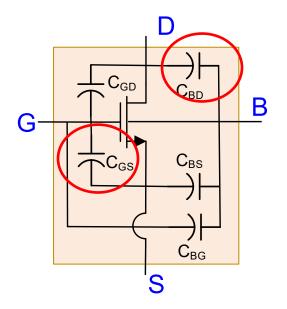
High Frequency Large Signal Model

High Frequency Small Signal Model

Often  $V_{BS}$ =0 and  $C_{BG}$ =0, so simplifies to



## **Parasitic Capacitance Implications**



The parasitic capacitances inherently introduce an upper limit on how fast either digital circuits or analog circuits can operate in a given process

Two parameters,  $f_{MAX}$  and  $f_{T}$ , (not defined yet) are two metric that are used to specify the fundamental speed limit in a semiconductor process

The dominant parasitic capacitances for most circuits are  $C_{GS}$  and  $C_{BD}$ 



# Stay Safe and Stay Healthy !

## End of Lecture 35